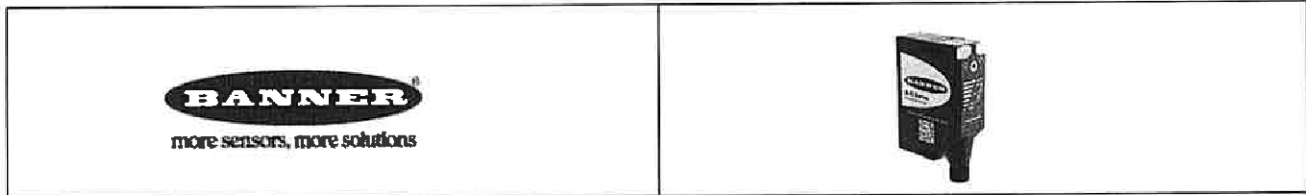




Device Test Report

TMG IO-Link Device Tool V5.1 - TS: Revision: 5.1.1 Build: 10296
TEngBas V5.1.1: Revision: 5.1.1 Build: 10267
Test ID: 842436151



Vendor ID : 451 Vendor : Banner Engineering Corporation
Device ID : 459009 Device : B55
IO-Link Version : V1.1 Product ID : B55
Firmware Revision : 1.1.70377 Hardware Revision : 1.0
Serial Number :

ISDU supported : True SIO mode supported : True
Process Data Input Bits : 16 Process Data Output Bits : 0
Min Cycle Time : 2900 µs Bitrate : COM2
Implemented Access Locks :
parameter="False" datastorage="False" localParameterization="True" localUserInterface="True"
IODD : Banner_Engineering-B55-20260717-IODD1.1.xml
Checker : IODD-Checker-V2025.1 IODD Stamp : 759857575
Test conditions: Test according IO-Link specification V1.1.5

=====

IODD Check: The IODD was checked with a valid IODD checker.

Test result : All test were passed with positiv result in complete operation.

=====

Test operated by : Company : Banner Engineering Corp.
Name : Cary Schneider
Signature : 

Testreport : Test System Version information

TMG IO-Link Device Tool V5.1 - TS:	Revision: 5.1.1	Build: 10296
Test Run Generation:	Revision: 5.1.1	Build: 10296
TEngBas V5.1.1:	Revision: 5.1.1	Build: 10267
Testcase DLL:	Name: ProtocolTests	Build: 10267
Test specifications:		
IO-Link Test Specification V1.1.5		
IO-Link Common Profiles V1.2.1 with snippets		

USB Master Firmware Revision: 3.2.7 / 1.3.E

Testreport : Test Configuration

Test variable for 8 Bit index access :

Index : 200 Length: 2
Data (hex) : 00 00

Test variable for 16 Bit index access :

Index : 1000 Length: 1
Data (hex) : 01

Test variable for 8 Bit index extended length :

Index : 24 Length: 16
Data (hex) : 20 20 20 20 20 20 20 20 20 20 20 20 20 20 20 20

Implemented system commands :

1 2 3 4 5 6 129 131 80 81 82 83 164 162
163

M-sequence Capability (hex) :

2B

Commands to generate events :

Event trigger 1 : appear value = 1	Index : 201
Event trigger 2 : appear value = 3	disappear value = 2
	disappear value = 4

===== Config Messages from Testcases =====

The testcase SDCI_TC_0080 TCD_APPS_DSUP_VIALOCALCHANGE is skipped because the device is not capable to change a parameter via local user interface

The testcase SDCI_TC_0124 TCD_DLIC_DEFP_ERRCOUNT is skipped because the device is not capable to change error count during the test

Device Test Report

Testreport Overview (1)

TC_Device_Identification	ok
Data Layer Tests V5.1.1.10267	
SDCI_TC_0034 TCD_DLPC_STUP_CYCTIME	ok
SDCI_TC_0035 TCD_DLPC_STUP_STUOPER1	ok
SDCI_TC_0306 TCD_DLPC_CHK_OVERRIDOK	ok
SDCI_TC_0036 TCD_DLPC_STUP_STUOPER2	ok
SDCI_TC_0037 TCD_DLPC_OPER_OPERSTUP1	ok
SDCI_TC_0038 TCD_DLPC_STAR_OPERSTAR2	ok
SDCI_TC_0039 TCD_DLPC_PREO_READDPP1	ok
SDCI_TC_0040 TCD_DLPC_PREO_WRITEDPP1	ok
SDCI_TC_0041 TCD_DLPC_PROP_SHORT_MESSAGE	ok
SDCI_TC_0043 TCD_DLPC_PROP_SIMRESET	ok
SDCI_TC_0044 TCD_DLPC_PROP_MSEQFAULT	ok
SDCI_TC_0377 TCD_DLPC_PROP_RECOVERY_TIME	ok
SDCI_TC_0045 TCD_DLPC_OPER_READ	ok
SDCI_TC_0046 TCD_DLPC_OPER_WRITE	ok
SDCI_TC_0047 TCD_DLPC_OPER_NEGWRITE	ok
SDCI_TC_0049 TCD_DLPC_OPER_SIMRESET	ok
SDCI_TC_0312 TCD_DLPC_OPER_OUTINVALID	ok
SDCI_TC_0313 TCD_DLPC_OPER_CONNECTIONLOSS	ok
SDCI_TC_0376 TCD_DLPC_OPER_PDVALIDITYINDICATION	ok
ISDU Tests V5.1.1.10267	
SDCI_TC_0052 TCD_DLPC_ISDU_AVAILMSEQCAP	ok
SDCI_TC_0053 TCD_DLIC_ISDU_IDLEBUSYCHECK	ok
SDCI_TC_0054 TCD_DLIC_ISDU_READINDEX8	ok
SDCI_TC_0055 TCD_DLIC_ISDU_READ8EXTLENGTH	ok
SDCI_TC_0056 TCD_DLIC_ISDU_WRITE8	ok
SDCI_TC_0057 TCD_DLIC_ISDU_READ8RESERVED	ok
SDCI_TC_0058 TCD_DLIC_ISDU_READ8NOSUBINDEX	ok
SDCI_TC_0059 TCD_DLIC_ISDU_READ16	ok
SDCI_TC_0060 TCD_DLIC_ISDU_WRITE16	ok
SDCI_TC_0061 TCD_DLIC_ISDU_READ16RESERVED	ok
SDCI_TC_0062 TCD_DLIC_ISDU_READ16NOSUBINDEX	ok
SDCI_TC_0063 TCD_DLIC_ISDU_WRITE8LENOVERRUN	ok
SDCI_TC_0064 TCD_DLIC_ISDU_WRITE8WRONGLEN	ok
SDCI_TC_0065 TCD_DLIC_ISDU_WRITE8WRONGCHECKSUM	ok
SDCI_TC_0066 TCD_DLIC_ISDU_WRITE8ROINDEX	ok
SDCI_TC_0067 TCD_DLIC_ISDU_ABORTREADREQ	ok
SDCI_TC_0068 TCD_DLIC_ISDU_ABORTREADRESP	ok
SDCI_TC_0309 TCD_DLIC_ISDU_ELEMENT_RETRY	ok
Event Tests V5.1.1.10267	
SDCI_TC_0069 TCD_DLIC_EVNT_OPERSINGLEEVENT	ok

Device Test Report

Testreport Overview (2)

SDCI_TC_0070 TCD_DLIC_EVNT_PROPSINGLEEVENT	ok
SDCI_TC_0071 TCD_DLIC_EVNT_OPEREVENTCLEAR	ok
SDCI_TC_0072 TCD_DLIC_EVNT_OPERCOMMINTERRUPT	ok
SDCI_TC_0073 TCD_DLIC_EVNT_OPERPOWERINTERRUPT	ok
SDCI_TC_0074 TCD_DLIC_EVNT_OPERAPPEARDISAPPEAR	ok
SDCI_TC_0075 TCD_DLIC_EVNT_OPERMULTEVENT	ok
SDCI_TC_0076 TCD_DLIC_EVNT_OPERSHORTEVENT	ok
SDCI_TC_0373 TCD_DLIC_DEFP_EVENTDEVSTAT	ok
Data Storage Tests V5.1.1.10267	
SDCI_TC_0077 TCD_APPS_DSUP_NOFLAG	ok
SDCI_TC_0078 TCD_APPS_DSUP_VIADOWNLOADSTORE	ok
SDCI_TC_0079 TCD_APPS_DSUP_VIADOWNLOADSTORENOWRITE	ok
SDCI_TC_0080 TCD_APPS_DSUP_VIALOCALCHANGE	ok
SDCI_TC_0081 TCD_APPS_DSUP_PARABREAKABORT	ok
SDCI_TC_0378 TCD_APPS_DSUP_INDEXLIST	ok
SDCI_TC_0082 TCD_APPS_DSDN_PARAMODIFICATION	ok
SDCI_TC_0083 TCD_APPS_DSDN_FACTORYRESET	ok
SDCI_TC_0084 TCD_APPS_DSDN_PARABREAKABORT	ok
SDCI_TC_0321 TCD_APPS_DSBP_APPLDSSINGLEPARAM	ok
SDCI_TC_0322 TCD_DS_APP_IDLEFLAGCLEAR	ok
SDCI_TC_0374 TCD_DS_APP_UPLOAD_FLAG_NON_VOLATILE	ok
Legacy Master Tests V5.1.1.10267	
SDCI_TC_0085 TCD_DLIC_COMP_STARTUP	ok
SDCI_TC_0086 TCD_DLIC_COMP_TYPE1INTERLEAVE	ok
SDCI_TC_0087 TCD_DLIC_COMP_PDINVALIDEVENT	ok
Direct Parameter Page 1 Tests V5.1.1.10267	
SDCI_TC_0089 TCD_DLPC_STDP_MASTERCYCLETIME	ok
SDCI_TC_0090 TCD_DLPC_STDP_MINCYCLETIME	ok
SDCI_TC_0091 TCD_DLPC_STDP_MSEQCAPABILITY	ok
SDCI_TC_0092 TCD_DLPC_STDP_REVISIONID	ok
SDCI_TC_0093 TCD_DLPC_STDP_PDIN	ok
SDCI_TC_0094 TCD_DLPC_STDP_PDOUT	ok
SDCI_TC_0095 TCD_DLPC_STDP_VENDORID	ok
SDCI_TC_0096 TCD_DLPC_STDP_DEVICEID	ok
SDCI_TC_0097 TCD_DLPC_STDP_FUNCTIONID	ok
SDCI_TC_0100 TCD_DLPC_STDP_READRESPAR	ok
SDCI_TC_0101 TCD_DLPC_STDP_WRITERESPAR	ok
SDCI_TC_0375 TCD_DLPC_STDP_MINCYCLETIME_VALID	ok
Predefined Device Parameter Tests V5.1.1.10267	
SDCI_TC_0104 TCD_DLIC_DEFP_SYSCMDRES	ok
SDCI_TC_0107 TCD_DLIC_DEFP_DSINDEX	ok
SDCI_TC_0108 TCD_DLIC_DEFP_DSRECORD	ok

Device Test Report

Testreport Overview (3)

SDCI_TC_0323 TCD_DLIC_DEFP_DSRECORDMARKER	ok
SDCI_TC_0109 TCD_DLIC_DEFP_ACCESSLOCKSVAL	ok
SDCI_TC_0110 TCD_DLIC_DEFP_ACCESSLOCKSINVAL	ok
SDCI_TC_0111 TCD_DLIC_DEFP_PROFILCHARAC	ok
SDCI_TC_0112 TCD_DLIC_DEFP_PDINDESC	ok
SDCI_TC_0113 TCD_DLIC_DEFP_PDOUTDESC	ok
SDCI_TC_0114 TCD_DLIC_DEFP_VENDORNAM	ok
SDCI_TC_0115 TCD_DLIC_DEFP_VENDORTEXT	ok
SDCI_TC_0116 TCD_DLIC_DEFP_PRODUCTNAM	ok
SDCI_TC_0117 TCD_DLIC_DEFP_PRODUCTID	ok
SDCI_TC_0118 TCD_DLIC_DEFP_PRODUCTTEXT	ok
SDCI_TC_0119 TCD_DLIC_DEFP_SERNUM	ok
SDCI_TC_0120 TCD_DLIC_DEFP_HARDREV	ok
SDCI_TC_0121 TCD_DLIC_DEFP_FIRMREV	ok
SDCI_TC_0122 TCD_DLIC_DEFP_TAGVALID	ok
SDCI_TC_0123 TCD_DLIC_DEFP_TAGINVALID	ok
SDCI_TC_0124 TCD_DLIC_DEFP_ERRCOUNT	ok
SDCI_TC_0128 TCD_DLIC_DEFP_DEVSTAT	ok
SDCI_TC_0129 TCD_DLIC_DEFP_DETAILDEVSTAT	ok
SDCI_TC_0131 TCD_DLIC_DEFP_DETAILDEVSTATACTIVE	ok
SDCI_TC_0132 TCD_DLIC_DEFP_PDIN	ok
SDCI_TC_0133 TCD_DLIC_DEFP_PDOUT	ok
SDCI_TC_0134 TCD_DLIC_DEFP_OFFTIMEVALID	ok
SDCI_TC_0136 TCD_DLIC_DEFP_PROFILEPARREAD	ok
SDCI_TC_0137 TCD_DLIC_DEFP_PROFILEPARWRITE	ok
SDCI_TC_0140 TCD_DLIC_DEFP_WRITETOREADONLY	ok
SDCI_TC_0141 TCD_DLIC_DEFP_WRITETOOSHORT	ok
SDCI_TC_0142 TCD_DLIC_DEFP_WRITETOOLONG	ok

Block Parameter Tests V5.1.1.10267

SDCI_TC_0143 TCD_DSBP_APPL_BPDOWNLOAD	ok
SDCI_TC_0144 TCD_DSBP_APPL_BPBREAKCMD	ok
SDCI_TC_0145 TCD_DSBP_APPL_BPBREAKRESET	ok
SDCI_TC_0146 TCD_DSBP_APPL_BPBREAKILLPARAM	ok
SDCI_TC_0147 TCD_DSBP_APPL_BPBREAK2DOWNLOADS	ok
SDCI_TC_0148 TCD_DSBP_APPL_BPBREAKLOCALLOCK	ok
SDCI_TC_0324 TCD_DSBP_APPL_UNEXPECTEDINIDLE	ok
SDCI_TC_0325 TCD_DSBP_APPL_WRITEINUPLOAD	ok
SDCI_TC_0326 TCD_DSBP_APPL_READINDOWNLOAD	ok
SDCI_TC_0327 TCD_DSBP_APPL_UNEXPINUPLOAD	ok
SDCI_TC_0328 TCD_DSBP_APPL_SWITCHSTATES	ok
SDCI_TC_0329 TCD_DSBP_APPL_UPBREAKRESET	ok
SDCI_TC_0330 TCD_DSBP_APPL_DNENDBYUPLOAD	ok

Device Test Report

Testreport Overview (4)

Parameter verification tests V5.1.1.10267

SDCI_TC_0149 TCD_IODD_PARV_IDENT	ok
SDCI_TC_0150 TCD_IODD_PARV_COMPROFILE	ok
SDCI_TC_0151 TCD_IODD_PARV_READVERIFY	ok
SDCI_TC_0152 TCD_IODD_PARV_WRITEVERIFY	ok
SDCI_TC_0157 TCD_IODD_PARV_INDEXCONSISTENT	ok

Functional System Tests V5.1.1.10267

SDCI_TC_0156 TCD_IODD_PARV_ACCESSLOCK	ok
SDCI_TC_0316 TCD_IODD_PARV_DEVICERESET	ok
SDCI_TC_0317 TCD_IODD_PARV_APPLRESET	ok
SDCI_TC_0155 TCD_IODD_PARV_FACTORYSETTINGS	ok
SDCI_TC_0318 TCD_IODD_PARV_BACKTOBOX	ok
SDCI_TC_0314 TCD_DLPC_DID_OVERWRITE_COMP	ok
SDCI_TC_0315 TCD_DLPC_DID_OVERRIDE_INCOMP	ok

Common Profile V5.1.1.10267

CP_TC_0001_TCD_CMPR_ID_ASCENDID	ok
CP_TC_0002_TCD_CMPR_ID_HIDDEN_I_D	ok
CP_TC_0003_TCD_CMPR_ID_LEASTPROFILE	ok
CP_TC_0004_TCD_CMPR_ID_EXTENSION	ok
CP_TC_0005_TCD_CMPR_ID_PDOUTDESCR	ok
CP_TC_0006_TCD_CMPR_ID_LOCATOR	ok

support of Physical Layer Tests V5.1.1.10267

SDCI_TC_0029 TCD_PHYL_INTF_TRDL	ok
SDCI_TC_0304 TCD_PHYL_INTF_UARTTRANSDELAY	ok
SDCI_TC_0305 TCD_PHYL_INTF_RESPONSETIME	ok
SDCI_TC_0319 TCD_PHYL_INTF_TRANSMISSIONERRORS	ok

Test Report Statistics:

Number of test cases overall : 140
Number of test cases ok : 140
Number of test cases ok with exception : 0
Number of test cases failed : 0
Number of test cases skipped : 0
Test Operation : complete